

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/594,173	DENG ET AL.	
Examiner	Art Unit	
MARK BLOUIN	2627	

	SEAR	CHED	
Class	Subclass	Date	Examiner

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Searched Classes 360 and 720 See EAST	10/2/2008	МВ
Text Searched Classes 360 and 720 See EAST	10/2/2008	МВ